

Form PTO-1449 (REV. 8-83)		US Dept. of Commerce PATENT & TRADEMARK OFFICE	ATTY DOCKET NO. 040852.98	APPLICATION NO. Patent 593,070, Divisional of Application No. 10/263,070 <u>10/788,206</u>		
INFORMATION DISCLOSURE STATEMENT (Use several sheets if necessary)		APPLICANT(S) Satoshi INOUE; Tatsuya SHIMODA				
		FILING DATE December 31, 2003				
U.S. PATENT DOCUMENTS						
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS
<i>AB</i>		5,747,121	05/1998	Okazaki et al.		
		5,767,930	06/1998	Kobayashi et al.		
		5,807,772	09/1998	Takemura		
		5,888,839	03/1999	Ino et al.		
		5,468,521	11/1995	Kanai et al.		
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		5,693,541	12/1997	Yamazaki et al.		
		5,589,962	12/1996	Yamamoto et al.		
<i>AB</i>		5,527,649	06/1996	Sato et al.		
<i>AB</i>		5,926,735	07/1999	Yamazaki et al.		
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		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUB CLASS
<i>AB</i>		JP-A-6-291291	10/1994	JAPAN		
		JP-A-8-288522	11/1996	JAPAN		
		JP-A-61-231714	10/1986	JAPAN		
<i>AB</i>		JP-A-8-62591	03/1996	JAPAN		
<i>AB</i>		WO 98/09333	03/1998	WIPO		
OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)						
<i>AB</i>		Sameshima, T. "Laser Beam Application to Thin Film Transistors," <u>Applied Surface Science</u> 96-98, (1996), pp. 352-358.				
EXAMINER	<i>Robert J. Dan</i>			DATE CONSIDERED <u>2/13/07</u>		
Examiner:	Initial if citation considered, whether or not citation is in conformance with M.P.E.P. 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.					



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Form PTO-1449 (REV. 1/06)		US Dept. of Commerce PATENT & TRADEMARK OFFICE		ATTY DOCKET NO. 040852.98	APPLICATION NO. 10/748,206
INFORMATION DISCLOSURE STATEMENT (Use several sheets if necessary)		APPLICANT(S) Satoshi INOUE et al.			
		FILING DATE December 31, 2003		GROUP 2812	
U.S. PATENT DOCUMENTS					
Examiner Initials	Cite No.	Document Number	Date	Name	
FOREIGN PATENT DOCUMENTS					
Examiner Initials	Cite No.	Document Number	Date	Country	With English Abstract With English Translation
OTHER DOCUMENTS					
Examiner Initials	Cite No.	(Including Author, Title, Date, Pertinent Pages, etc.)			
MM	1.	Sameshima T., Laser beam application to the thin film transistors, Applied Surface Science, April 2, 1996 Vol. 96-98			
		Pages 352-358			
EXAMINER <i>Robert A.</i>		DATE CONSIDERED <i>2/3/07</i>			
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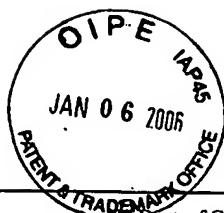
Form PTO-1449 (REV. 1/06)			Dept. of Commerce PATENT & TRADEMARK OFFICE		ATTY DOCKET NO. 040852.98		APPLICATION NO. 10/748,206	
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Examiner Initials	Cite No.	Document Number	Date	Name				
FOREIGN PATENT DOCUMENTS								
Examiner Initials	Cite No.	Document Number	Date	Country	With English Abstract	With English Translation		
1.	JP A 07-504782 (corresponds to reference 2)	05/25/1995	Japan					
2.	WO 93/16491	08/19/1993	WIPO					
3.	JP A 07-294961	11/10/1995	Japan	X	X			
OTHER DOCUMENTS								
Examiner Initials	Cite No.	(Including Author, Title, Date, Pertinent Pages, etc.)						
EXAMINER				DATE CONSIDERED 2/3/07				
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Form PTO-199 (REV. 8-83)		US Dept. of Commerce PATENT & TRADEMARK OFFICE		ATTY DOCKET NO. 040852.98		APPLICATION NO. 10/748,206	
INFORMATION DISCLOSURE STATEMENT (Use several sheets if necessary)				APPLICANT(S) Satoshi INOUE et al.			
				FILING DATE December 31, 2003		GROUP 2812	
		U.S. PATENT DOCUMENTS					
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME		CLASS	SUB CLASS
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY		CLASS	SUB CLASS
RB	1	JP07-098460A (w/machine translation)	04/1995	Japan			
	2	JP08-250745A (w/machine translation)	09/1996	Japan			
	3	JP08-262474A (w/machine translation)	10/1996	Japan			
	4	JP08-262475A (w/machine translation)	10/1996	Japan			
	5	JP08-234796A (w/machine translation)	09/1996	Japan			
	6	JP08-278519A (w/machine translation)	10/1996	Japan			
	7	JP05-218365A (w/machine translation)	08/1993	Japan			
	8	JP08-240814A (w/machine translation)	09/1996	Japan			
	9	JP06-202160A (w/machine translation)	07/1994	Japan			
		JP63-101830A (w/Abstract)	05/1988	Japan			
		JP63-101832A (w/Abstract)	05/1988	Japan			
RB		JP04-170520A (w/Abstract)	06/1992	Japan			
OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)							
EXAMINER		<i>John A.</i>				DATE CONSIDERED 2/3/07	
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		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUB CLASS
<i>AB</i>	1	WO 92/12453	07/23/1992	WIPO		
<i>AB</i>	2	JP-A-06-504139	05/12/1994	JAPAN		
<i>AB</i>	3	JP-A-06-219052 (w/English-language Abstract & Translation)	08/09/1994	JAPAN		
<i>AB</i>	4	JP-A-06-118441 (w/English-language Abstract & Translation)	04/28/1994	JAPAN		
OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)						
EXAMINER	<i>Abelard Jr</i>				DATE CONSIDERED <i>2/13/07</i>	
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